

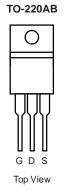
P9NK90Z-VB Datasheet

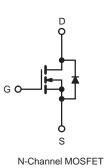
N-Channel 900V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	0.95			
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	900	V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	la la	7.0		
	VGS at 10 V	T _C = 100 °C	ID	5.5	A	
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Current ^a			I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation T _C = 25 °C			PD	190	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s			300 ^d			
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 23 mH, $R_g = 25 \Omega$, $I_{AS} = 7.8 \text{ A}$ (see fig. 12). c. $I_{SD} \le 7.8 \text{ A}$, dl/dt $\le 140 \text{ A/}\mu\text{s}$, $V_{DD} \le 600 \text{ V}$, $T_J \le 150 \text{ °C}$. d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

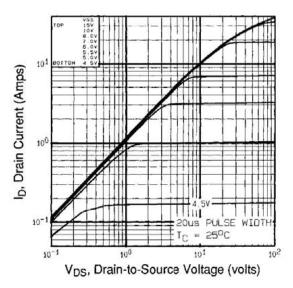


THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		40				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24		-	- °C/W 0.65			
Maximum Junction-to-Case (Drain)	R _{thJC}	-		0.65				
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL	1	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		1				•	•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$		-	-	± 100	nA
		V _{DS} =	= 900 V, V _G	_{is} = 0 V	-	-	100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 720 \	$V_{\rm GS} = 0$	/, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		₀ = 5.6 A ^b	-	0.95	-	Ω
Forward Transconductance	g fs	V _{DS} =	100 V, I _D :	= 5.6 A ^b	5.6	-	-	S
Dynamic	-					1	1	
Input Capacitance	C _{iss}		$\lambda = 0$	1	-	3100	-	
Output Capacitance	Coss	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	800	-	pF	
Reverse Transfer Capacitance	C _{rss}			-	490	-		
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ see fig. 6 and } 13^{\text{b}}$		-	-	24	nC
Gate-Drain Charge	Q _{gd}	-	300 1	ig. o and 15	-	-	110	1
Turn-On Delay Time	t _{d(on)}				-	19	-	ns
Rise Time	tr		= 400 V, I _D		-	38	-	
Turn-Off Delay Time	t _{d(off)}	R _g =	6.2 Ω, R _D		-	120	-	
Fall Time	t _f	see fig. 10 ^b		-	39	-	1	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	- nH	
Internal Source Inductance	Ls			-	13	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0		
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A	
Body Diode Voltage	V _{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 5.6 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C, } I_{F} = 5.6 \text{ A,}$ $dl/dt = 100 \text{ A/}\mu\text{s}^{b}$		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	m-on time	is negligible (turn	-on is doi	minated k	by L_{S} and	L _D)

Notes

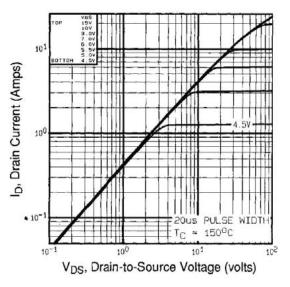
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







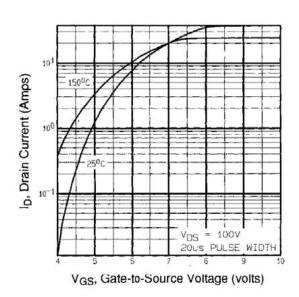
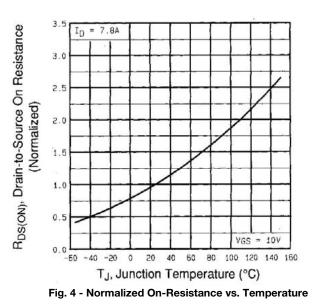


Fig. 3 - Typical Transfer Characteristics



P9NK90Z-VB



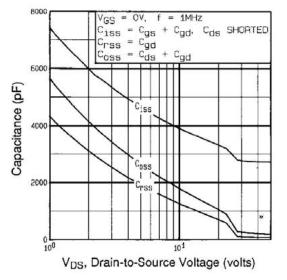
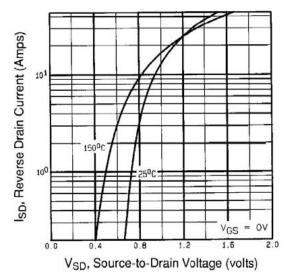


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage





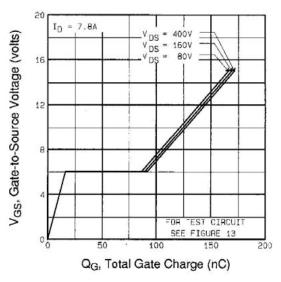
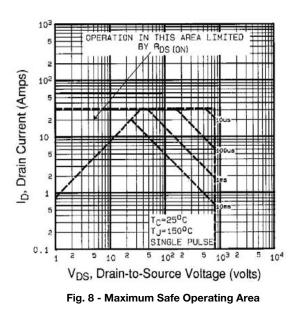


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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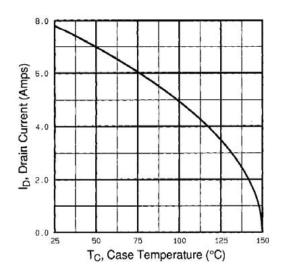


Fig. 9 - Maximum Drain Current vs. Case Temperature

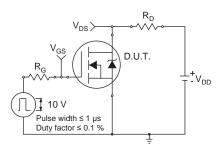


Fig. 10a - Switching Time Test Circuit

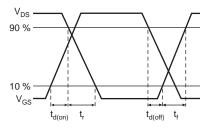


Fig. 10b - Switching Time Waveforms

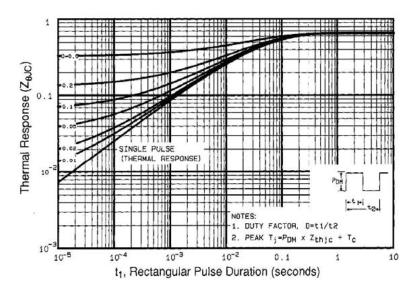


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



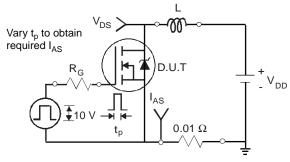


Fig. 12a - Unclamped Inductive Test Circuit

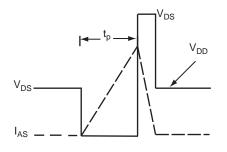


Fig. 12b - Unclamped Inductive Waveforms

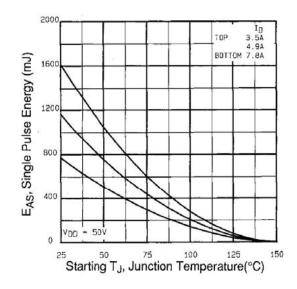


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

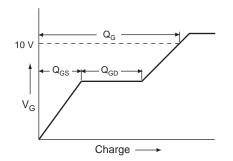


Fig. 13a - Basic Gate Charge Waveform

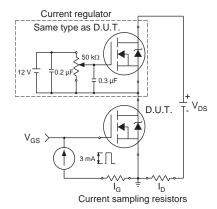
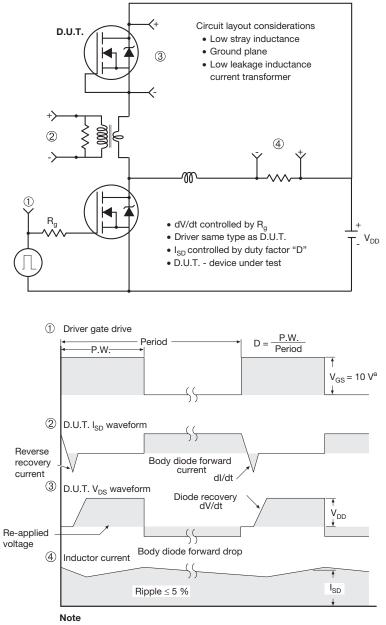


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

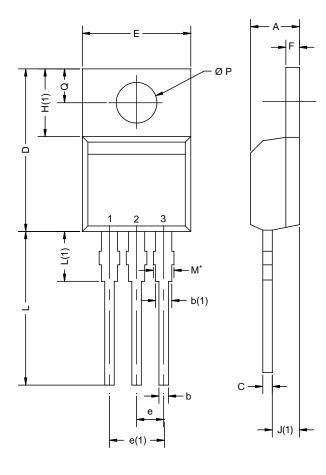


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12		•	

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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